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## REVISION HISTORY

### 9/2017—Rev. A to Rev. B

Change to Features Section .....	1
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### 3/2009—Rev. 0 to Rev. A

Changes to Power Requirements, $I_{DD}$ , Digital Inputs = 5 V Parameter, Table 1.....	4
Changes to $t_{ON}$ Parameter and Power Requirements, $I_{DD}$ , Digital Inputs = 5 V Parameter, Table 2.....	5

### 2/2007—Rev. 0: Initial Version

## SPECIFICATIONS

## DUAL SUPPLY

$V_{DD} = 15\text{ V} \pm 10\%$ ,  $V_{SS} = -15\text{ V} \pm 10\%$ , GND = 0 V, unless otherwise noted.

Table 1.

Parameter	Temperature			Unit	Test Conditions/Comments
	25°C	−40°C to +85°C	−40°C to +125°C		
ANALOG SWITCH					
Analogue Signal Range			V <sub>DD</sub> to V <sub>SS</sub>	V	V <sub>DD</sub> = +13.5 V, V <sub>SS</sub> = −13.5 V, V <sub>S</sub> = ±10 V, I <sub>S</sub> = −1 mA (see Figure 23)
On Resistance, R <sub>ON</sub>	120 200	240	270	Ω typ Ω max	
On Resistance Match Between Channels, ΔR <sub>ON</sub>	2.5 6	10	12	Ω typ Ω max	V <sub>S</sub> = ±10 V, I <sub>S</sub> = −1 mA
On Resistance Flatness, R <sub>FLAT(ON)</sub>	20 64	76	83	Ω typ Ω max	V <sub>S</sub> = −5 V/0 V/+5 V; I <sub>S</sub> = −1 mA
LEAKAGE CURRENTS					
Source Off Leakage, I <sub>S</sub> (Off)	±0.002 ±0.1	±0.6	±1	nA typ nA max	V <sub>DD</sub> = +16.5 V, V <sub>SS</sub> = −16.5 V V <sub>S</sub> = ±10 V, V <sub>D</sub> = ±10 V (see Figure 24)
Drain Off Leakage, I <sub>D</sub> (Off)	±0.002 ±0.1	±0.6	±1	nA typ nA max	
Channel On Leakage, I <sub>D</sub> , I <sub>S</sub> (On)	±0.01 ±0.2	±0.6	±1	nA typ nA max	V <sub>S</sub> = V <sub>D</sub> = ±10 V (see Figure 25)
DIGITAL INPUTS					
Input High Voltage, V <sub>INH</sub>			2.0	V min	V <sub>IN</sub> = V <sub>INL</sub> or V <sub>INH</sub>
Input Low Voltage, V <sub>INL</sub>			0.8	V max	
Input Current, I <sub>INL</sub> or I <sub>INH</sub>	0.005			μA typ μA max	
			±0.1	μA max pF typ	
Digital Input Capacitance, C <sub>IN</sub>	2.5				
DYNAMIC CHARACTERISTICS <sup>1</sup>					
t <sub>ON</sub>	130 170	210	240	ns typ ns max	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF, V <sub>S</sub> = 10 V (see Figure 26)
t <sub>OFF</sub>	85 105	130	140	ns typ ns max	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF, V <sub>S</sub> = 10 V (see Figure 26)
Break-Before-Make Time Delay (ADG1223 Only), t <sub>BBM</sub>	40		10	ns typ ns min	R <sub>L</sub> = 300 Ω, C <sub>L</sub> = 35 pF, V <sub>S1</sub> = V <sub>S2</sub> = 10 V (see Figure 27)
Charge Injection, Q <sub>INJ</sub>	0.1			pC typ	V <sub>S</sub> = 0 V, R <sub>S</sub> = 0 Ω, C <sub>L</sub> = 1 nF (see Figure 28)
Off Isolation	75			dB typ	
					R <sub>L</sub> = 50 Ω, C <sub>L</sub> = 1 pF, f = 1 MHz (see Figure 29)



Parameter	Temperature			Unit	Test Conditions/Comments
	25°C	–40°C to +85°C	–40°C to +125°C		
Drain Off Leakage, $I_D$ (Off)	±0.002 ±0.1	±0.6	±1	nA typ nA max	$V_S = 1\text{ V}/10\text{ V}$ , $V_D = 10\text{ V}/1\text{ V}$ (see Figure 24)
Channel On Leakage, $I_D$ , $I_S$ (On)	±0.01 ±0.2	±0.6	±1	nA typ nA max	$V_S = V_D = 1\text{ V}$ or $10\text{ V}$ (see Figure 25)
DIGITAL INPUTS					
Input High Voltage, $V_{INH}$			2.0	V min	$V_{IN} = V_{INL}$ or $V_{INH}$
Input Low Voltage, $V_{INL}$			0.8	V max	
Input Current, $I_{INL}$ or $I_{INH}$	0.001		±0.1	µA typ µA max	
Digital Input Capacitance, $C_{IN}$	3			pF typ	
DYNAMIC CHARACTERISTICS <sup>1</sup>					
$t_{ON}$	190 250	300	345	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ , $V_S = 8\text{ V}$ (see Figure 26)
$t_{OFF}$	120 150	190	225	ns typ ns max	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ , $V_S = 8\text{ V}$ (see Figure 26)
Break-Before-Make Time Delay (ADG1223 Only), $t_{BBM}$	70		10	ns typ ns min	$R_L = 300\ \Omega$ , $C_L = 35\text{ pF}$ , $V_{S1} = V_{S2} = 8\text{ V}$ (see Figure 27)
Charge Injection, $Q_{INJ}$	0.2			pC typ	$V_S = 6\text{ V}$ , $R_S = 0\ \Omega$ , $C_L = 1\text{ nF}$ (see Figure 28)
Off Isolation	75			dB typ	$R_L = 50\ \Omega$ , $C_L = 1\text{ pF}$ , $f = 1\text{ MHz}$ (see Figure 29)
Channel-to-Channel Crosstalk	90			dB typ	$R_L = 50\ \Omega$ , $C_L = 1\text{ pF}$ , $f = 1\text{ MHz}$ (see Figure 30)
–3 dB Bandwidth $C_S$ (Off)	550			MHz typ	$R_L = 50\ \Omega$ , $C_L = 1\text{ pF}$ (see Figure 31) $V_S = 6\text{ V}$ , $f = 1\text{ MHz}$
$C_D$ (Off)	2.1 2.6			pF typ pF max	$V_S = 6\text{ V}$ , $f = 1\text{ MHz}$
$C_D$ , $C_S$ (On)	2.1 2.6			pF typ pF max	
	3.8 4.6			pF typ pF max	$V_S = 6\text{ V}$ , $f = 1\text{ MHz}$
POWER REQUIREMENTS					
$I_{DD}$	0.001		1.0	µA typ µA max	$V_{DD} = 13.2\text{ V}$ Digital inputs = 0 V or $V_{DD}$ Digital inputs = 0 V or $V_{DD}$
	140		190	µA typ µA max	Digital inputs = 5 V Digital inputs = 5 V
$V_{DD}$			5/16.5	V min/max	$V_{SS} = 0\text{ V}$ , $GND = 0\text{ V}$

<sup>1</sup> Guaranteed by design, not subject to production test.

## ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ\text{C}$ , unless otherwise noted.

Table 3.

Parameter	Rating
$V_{DD}$ to $V_{SS}$	35 V
$V_{DD}$ to GND	–0.3 V to +25 V
$V_{SS}$ to GND	+0.3 V to –25 V
Analog Inputs <sup>1</sup>	$V_{SS} - 0.3\text{ V}$ to $V_{DD} + 0.3\text{ V}$ or 30 mA, whichever occurs first
Digital Inputs <sup>1</sup>	GND – 0.3 V to $V_{DD} + 0.3\text{ V}$ or 30 mA, whichever occurs first
Peak Current, S or D	100 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current per Channel, S or D	30 mA
Operating Temperature Range	–40°C to +125°C
Storage Temperature Range	–65°C to +150°C
Junction Temperature	150°C
Reflow Soldering Peak Temperature, Pb free	260°C

<sup>1</sup> Overvoltages at IN, S, or D are clamped by internal diodes. Current must be limited to the maximum ratings given.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

## THERMAL RESISTANCE

$\theta_{JA}$  is specified for the worst-case conditions, that is, a device soldered in a circuit board for surface-mount packages.

Table 4. Thermal Resistance

Package Type	$\theta_{JA}$	$\theta_{JC}$	Unit
10-Lead MSOP (4-Layer Board)	206	44	°C/W

## ESD CAUTION



**ESD (electrostatic discharge) sensitive device.** Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

## PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

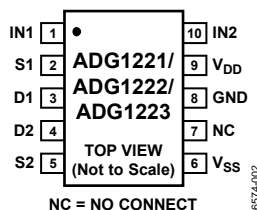


Figure 3. 10-Lead MSOP Pin Configuration

Table 5. Pin Function Descriptions

Pin No.	Mnemonic	Description
1	IN1	Logic Control Input.
2	S1	Source Terminal. Can be an input or output.
3	D1	Drain Terminal. Can be an input or output.
4	D2	Drain Terminal. Can be an input or output.
5	S2	Source Terminal. Can be an input or output.
6	V <sub>SS</sub>	Most Negative Power Supply Potential.
7	NC	No Connect.
8	GND	Ground (0 V) Reference.
9	V <sub>DD</sub>	Most Positive Power Supply Potential.
10	IN2	Logic Control Input.

Table 6. ADG1221/ADG1222 Truth Table

ADG1221 INx	ADG1222 INx	Switch Condition
1	0	On
0	1	Off

Table 7. ADG1223 Truth Table

ADG1223 INx	Switch 1 Condition	Switch 2 Condition
0	Off	On
1	On	Off

## TERMINOLOGY

### **I<sub>DD</sub>**

The positive supply current.

### **I<sub>SS</sub>**

The negative supply current.

### **V<sub>D</sub> (V<sub>S</sub>)**

The analog voltage on Terminal D and Terminal S.

### **R<sub>ON</sub>**

The ohmic resistance between Terminal D and Terminal S.

### **R<sub>FLAT(ON)</sub>**

Flatness is defined as the difference between the maximum and minimum value of on resistance, as measured over the specified analog signal range.

### **I<sub>S</sub> (Off)**

The source leakage current with the switch off.

### **I<sub>D</sub> (Off)**

The drain leakage current with the switch off.

### **I<sub>D</sub>, I<sub>S</sub> (On)**

The channel leakage current with the switch on.

### **V<sub>INL</sub>**

The maximum input voltage for Logic 0.

### **V<sub>INH</sub>**

The minimum input voltage for Logic 1.

### **I<sub>INL</sub> (I<sub>INH</sub>)**

The input current of the digital input.

### **C<sub>S</sub> (Off)**

The off switch source capacitance, measured with reference to ground.

### **C<sub>D</sub> (Off)**

The off switch drain capacitance, measured with reference to ground.

### **C<sub>D</sub>, C<sub>S</sub> (On)**

The on switch capacitance, measured with reference to ground.

### **C<sub>IN</sub>**

The digital input capacitance.

### **t<sub>ON</sub>**

The delay between applying the digital control input and the output switching on (see Figure 26).

### **t<sub>OFF</sub>**

The delay between applying the digital control input and the output switching off (see Figure 26).

### **t<sub>BMM</sub>**

Off time or on time measured between the 90% points of both switches, when switching from one address state to another (ADG1223 only).

### **Q<sub>INJ</sub> (Charge Injection)**

A measure of the glitch impulse transferred from the digital input to the analog output during switching.

### **Off Isolation**

A measure of unwanted signal coupling through an off switch.

### **Crosstalk**

A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

### **-3 dB Bandwidth**

The frequency at which the output is attenuated by 3 dB.

### **On Response**

The frequency response of the on switch.

### **Insertion Loss**

The loss due to the on resistance of the switch.

### **THD + N (Total Harmonic Noise Plus Distortion)**

The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

### **ACPSRR (AC Power Supply Rejection Ratio)**

Measures the ability of a part to avoid coupling noise and spurious signals that appear on the supply voltage pin to the output of the switch. The dc voltage on the device is modulated by a sine wave of 0.62 V p-p. The ratio of the amplitude of signal on the output to the amplitude of the modulation is the ACPSRR.

## TYPICAL PERFORMANCE CHARACTERISTICS

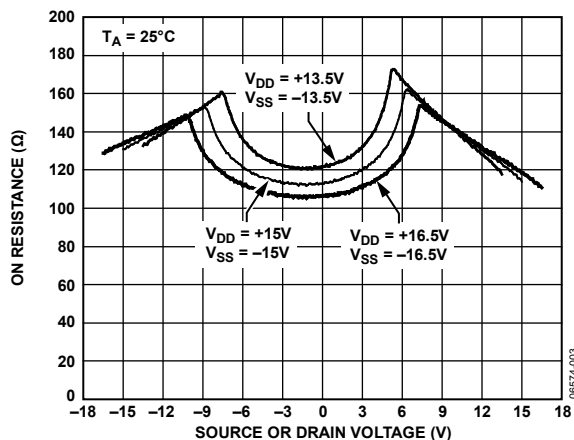
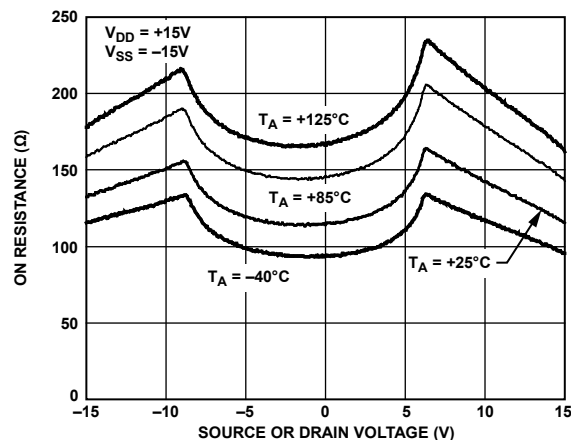
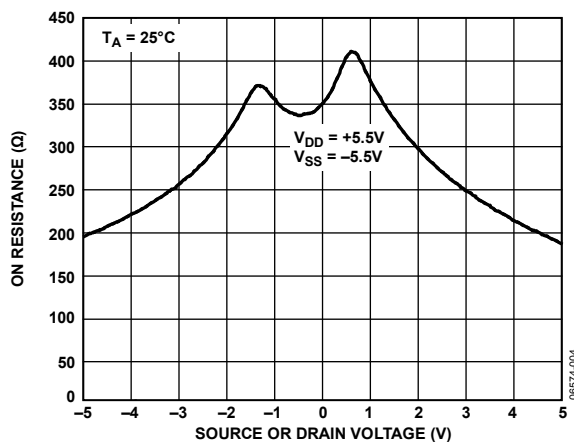
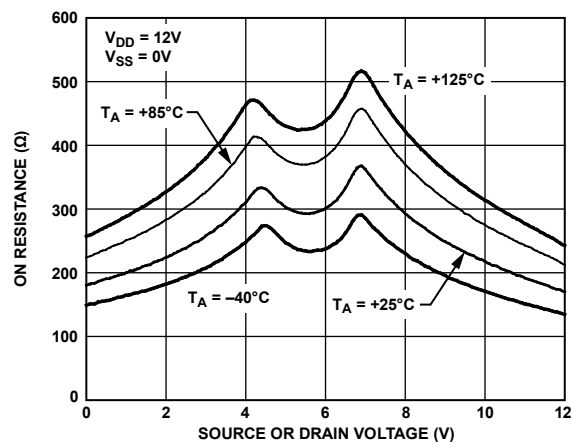
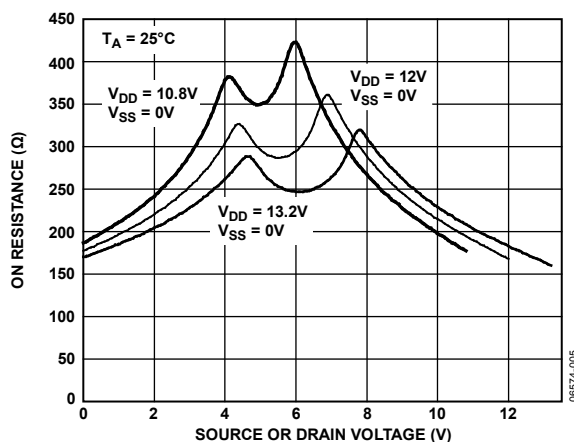
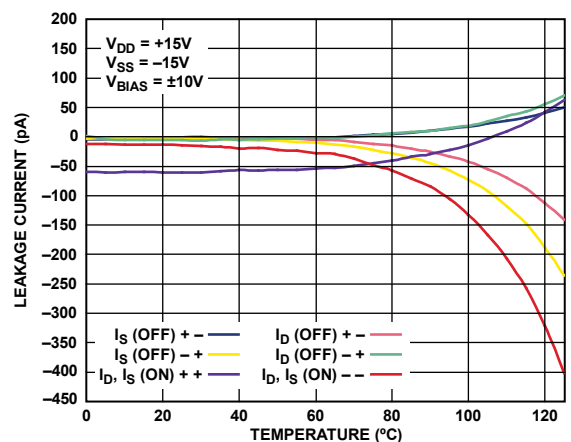
Figure 4. On Resistance as a Function of  $V_S$  ( $V_D$ ), Dual SupplyFigure 7. On Resistance as a Function of  $V_S$  ( $V_D$ ) for Different Temperatures, Dual SupplyFigure 5. On Resistance as a Function of  $V_S$  ( $V_D$ ), Dual SupplyFigure 8. On Resistance as a Function of  $V_S$  ( $V_D$ ) for Different Temperatures, Single SupplyFigure 6. On Resistance as a Function of  $V_S$  ( $V_D$ ), Single Supply

Figure 9. Leakage Current as a Function of Temperature, Dual Supply



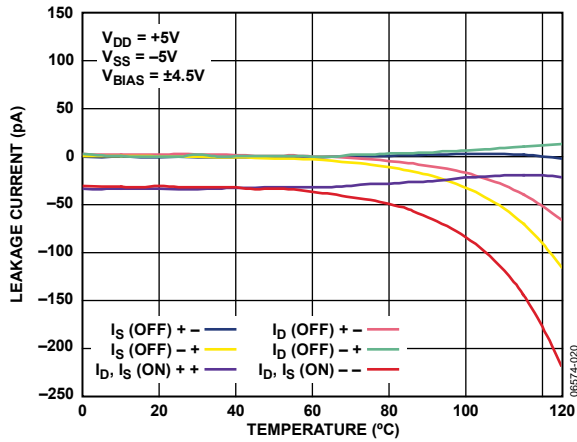


Figure 10. Leakage Current as a Function of Temperature, Dual Supply

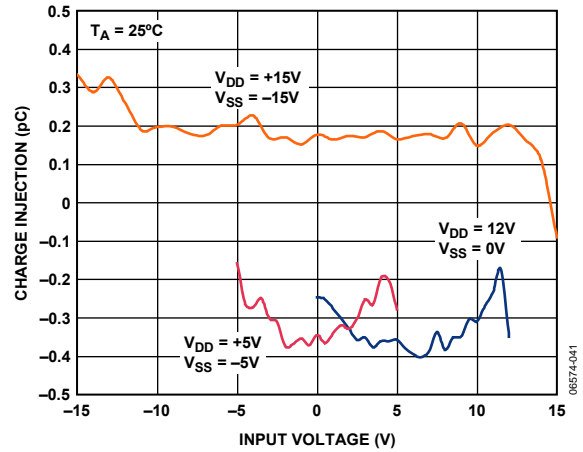


Figure 13. Charge Injection vs. Input Voltage

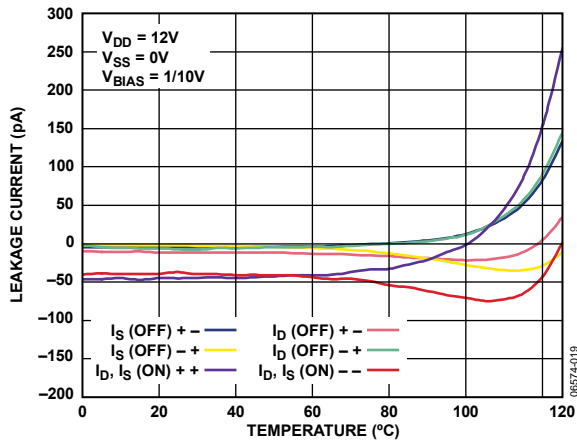


Figure 11. Leakage Current as a Function of Temperature, Single Supply

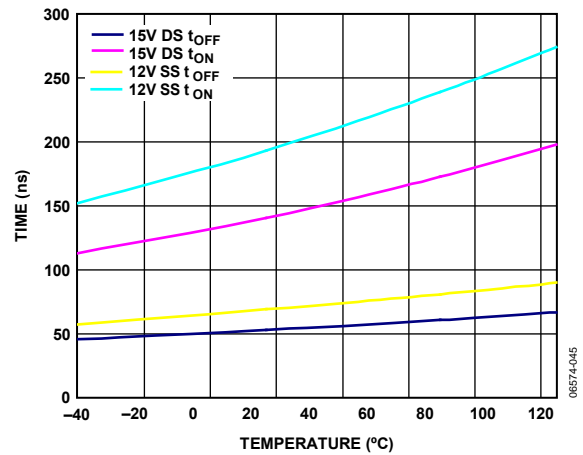


Figure 14.  $t_{ON}/t_{OFF}$  vs. Temperature

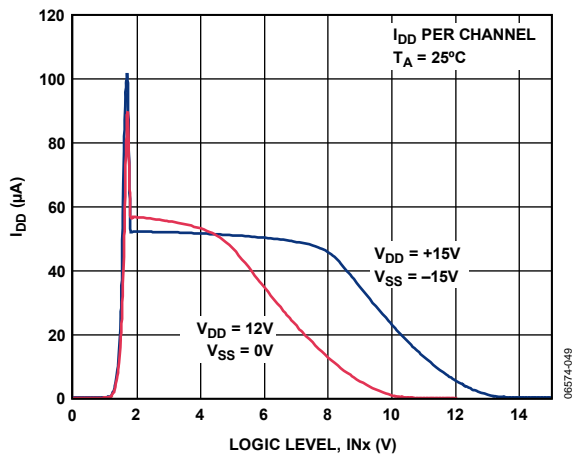


Figure 12.  $I_{DD}$  vs. Logic Level

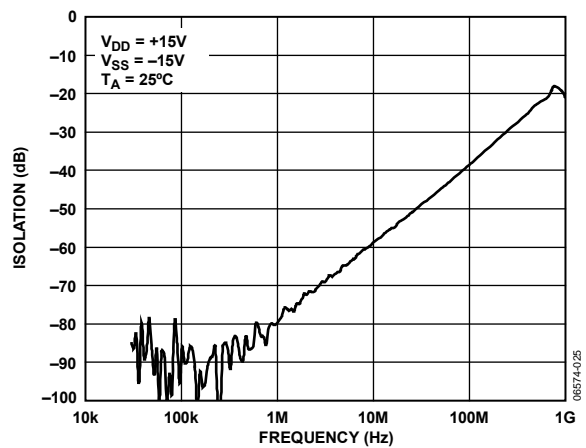


Figure 15. Off Isolation vs. Frequency

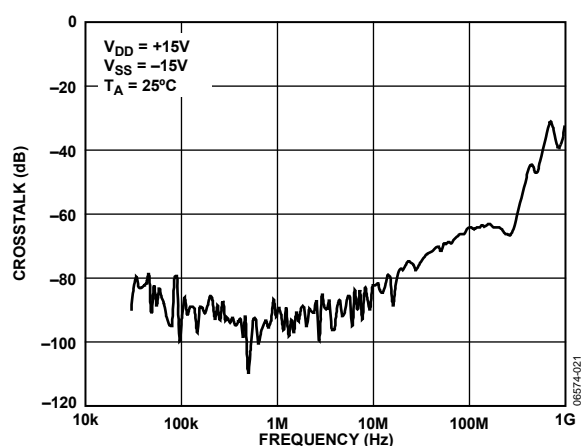


Figure 16. Crosstalk vs. Frequency

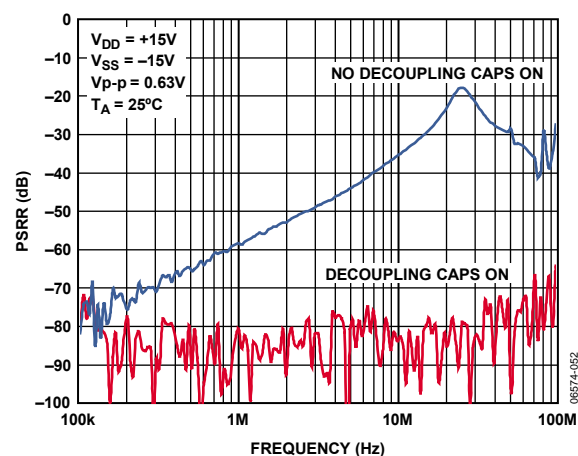


Figure 18. ACPSRR vs. Frequency

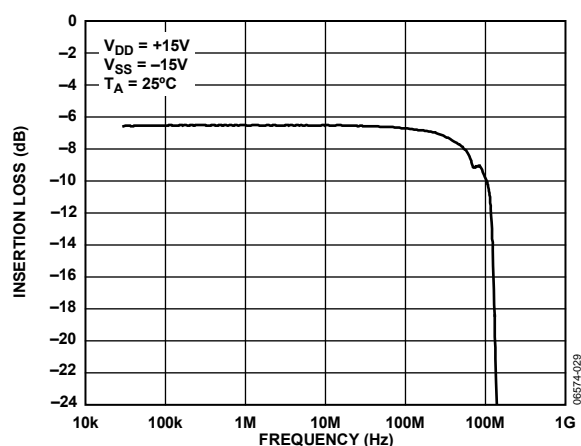


Figure 17. Insertion Loss vs. Frequency

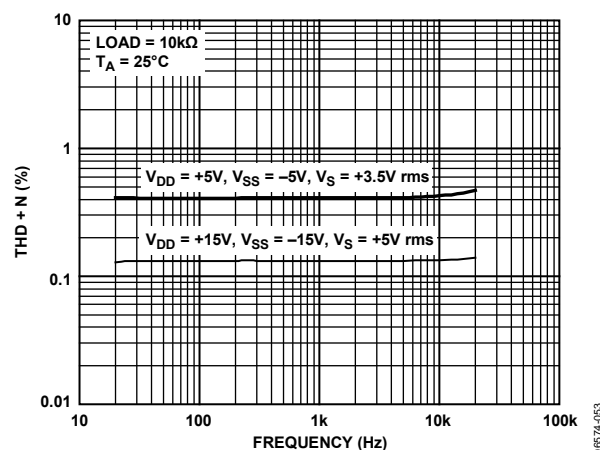


Figure 19. THD + N vs. Frequency

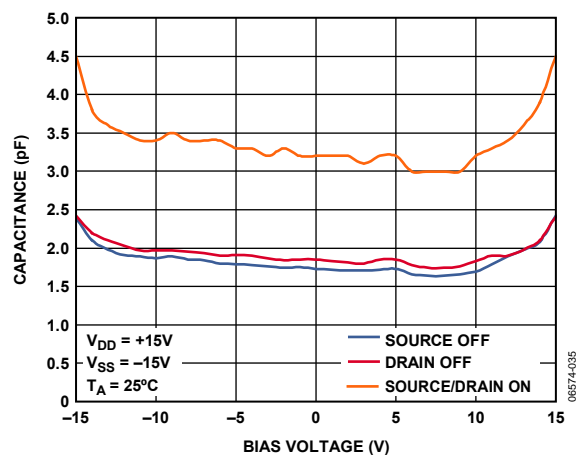


Figure 20. Capacitance vs. Bias Voltage

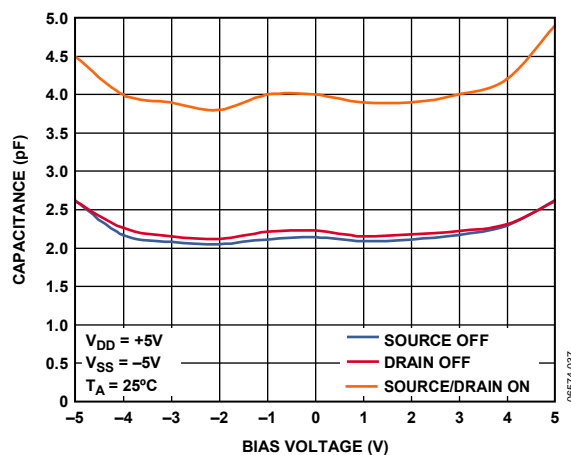


Figure 22. Capacitance vs. Bias Voltage

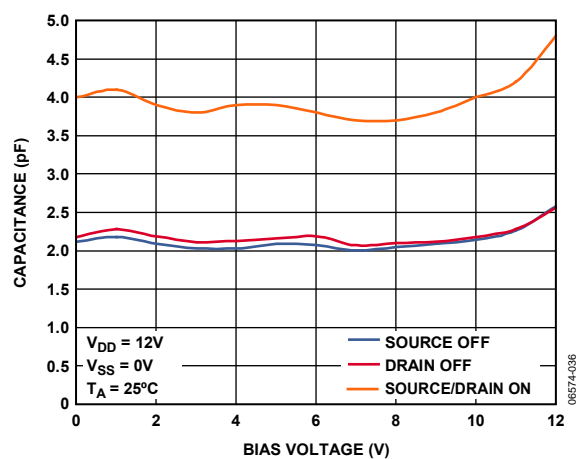


Figure 21. Capacitance vs. Bias Voltage

## TEST CIRCUITS

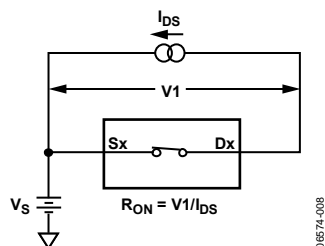


Figure 23. Test Circuit 1—On Resistance

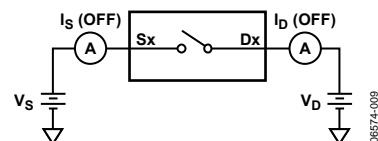


Figure 24. Test Circuit 2—Off Leakage

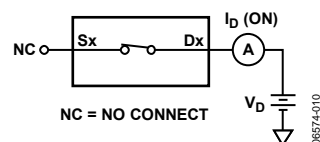


Figure 25. Test Circuit 3—On Leakage

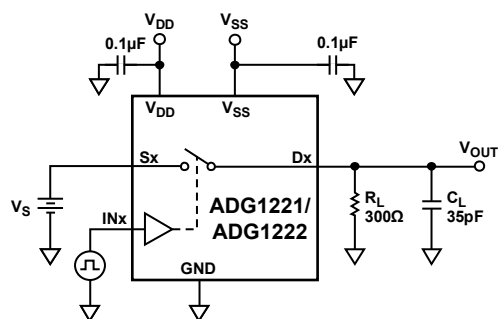


Figure 26. Test Circuit 4—Switching Times

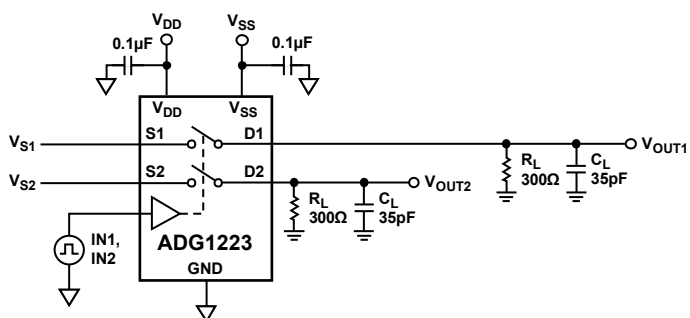
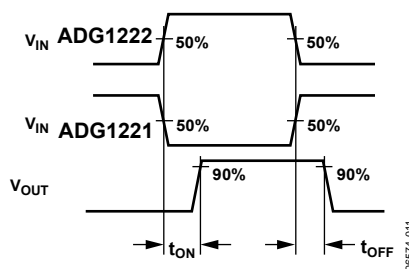


Figure 27. Test Circuit 5—Break-Before-Make Time Delay

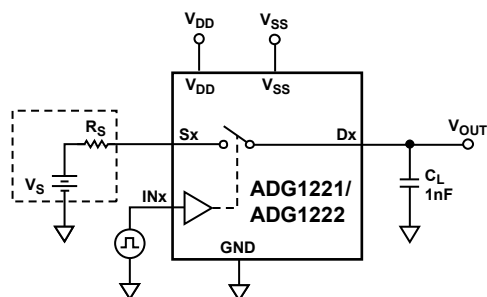
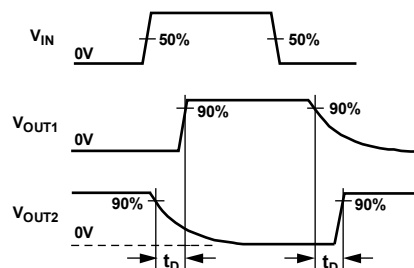
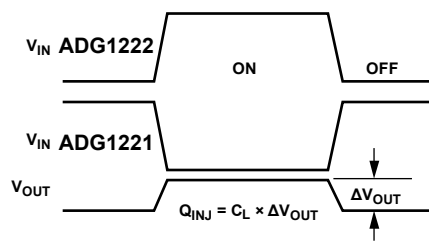


Figure 28. Test Circuit 6—Charge Injection



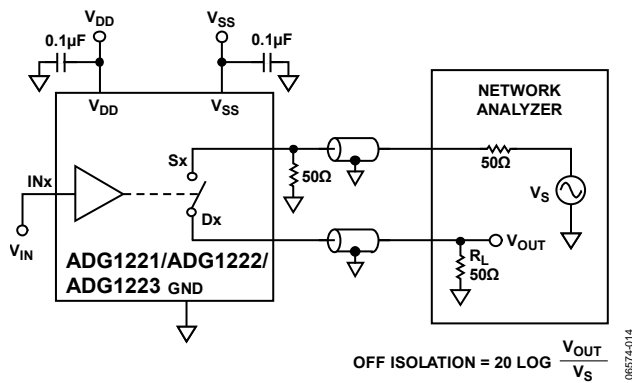


Figure 29. Test Circuit 7—Off Isolation

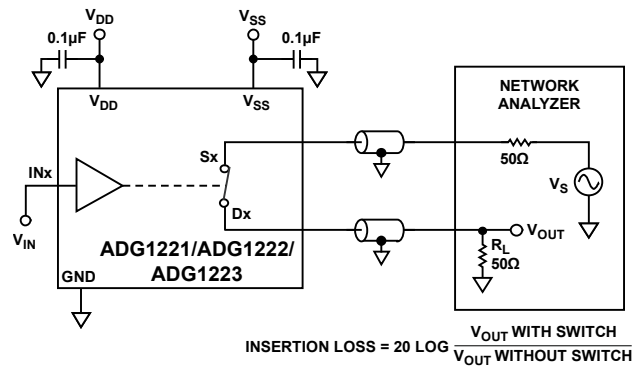


Figure 31. Test Circuit 9—Bandwidth

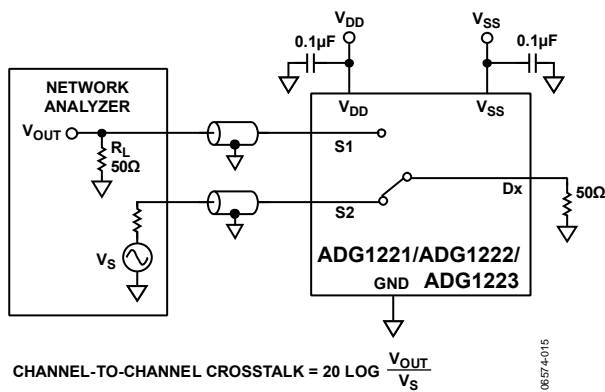


Figure 30. Test Circuit 8—Channel-to-Channel Crosstalk

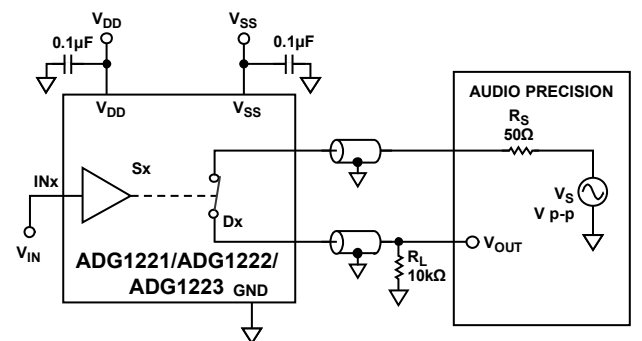
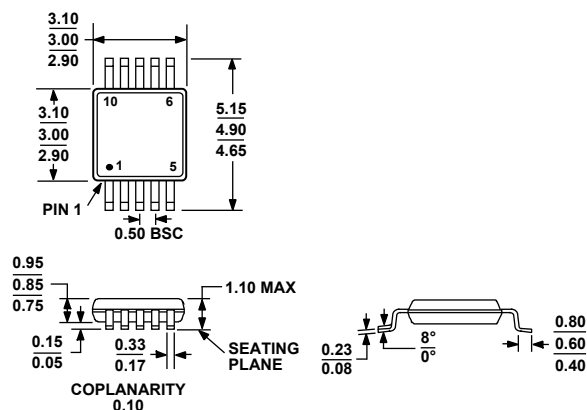


Figure 32. Test Circuit 10—Total Harmonic Distortion + Noise

## OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MO-187-BA

Figure 33. 10-Lead Mini Small Outline Package [MSOP]  
(RM-10)

Dimensions shown in millimeters

## ORDERING GUIDE

Model <sup>1</sup>	Temperature Range	Package Description	Package Option	Branding
ADG1221BRMZ	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S27
ADG1221BRMZ-REEL7	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S27
ADG1222BRMZ	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S28
ADG1222BRMZ-REEL7	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S28
ADG1223BRMZ	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S2J
ADG1223BRMZ-REEL7	−40°C to +125°C	10-Lead Mini Small Outline Package (MSOP)	RM-10	S2J

<sup>1</sup> Z = Pb-free part.

## NOTES